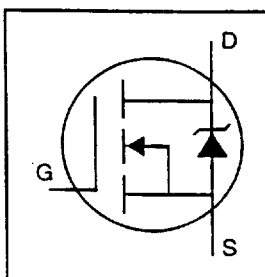


- Advanced Process Technology
- Dynamic dv/dt Rating
- 150°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated

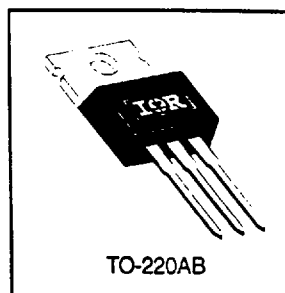
Description

Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 watts. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.



$V_{DS} = 250V$
 $R_{DS(on)} = 0.125\Omega$
 $I_D = 20A$



Absolute Maximum Ratings

	Parameter	Max.	Units
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	20	A
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	13	
I_{DM}	Pulsed Drain Current ①	80	
$P_D @ T_C = 25^\circ C$	Power Dissipation	125	W
	Linear Derating Factor	1.0	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
E_{AS}	Single Pulse Avalanche Energy ②	420	mJ
I_{AR}	Avalanche Current ③	12	A
E_{AR}	Repetitive Avalanche Energy ④	13	mJ
dv/dt	Peak Diode Recovery dv/dt ⑤	3.2	V/ns
T_J	Operating Junction and	-55 to +150	°C
T_{STG}	Storage Temperature Range		
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting torque, 6-32 or M3 screw	10 lbf•in (1.1N•m)	

Thermal Resistance

	Parameter	Typ.	Max.	Units
R_{JC}	Junction-to-Case	—	1.0	°C/W
R_{CS}	Case-to-Sink, Flat, Greased Surface	0.50	—	
R_{JA}	Junction-to-Ambient	—	62	

Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	250	—	—	V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T$	—	0.37	—	V/ $^\circ\text{C}$	Reference to $25^\circ\text{C}, I_D = 1mA$
$R_{DS(on)}$	—	—	0.125	Ω	$V_{GS} = 10V, I_D = 12A$ ④
$V_{GS(th)}$	2.0	—	4.0	V	$V_{DS} = V_{GS}, I_D = 250\mu A$
g_{fs}	15	—	—	S	$V_{DS} = 50V, I_D = 12A$
I_{DSS}	—	—	25	μA	$V_{DS} = 250V, V_{GS} = 0V$
	—	—	250	μA	$V_{DS} = 200V, V_{GS} = 0V, T_J = 125^\circ\text{C}$
I_{GSS}	—	—	100	nA	$V_{GS} = 20V$
	—	—	-100	nA	$V_{GS} = -20V$
Q_g	—	—	190	nC	$I_D = 12A$
Q_{gs}	—	—	20	nC	$V_{DS} = 200V$
Q_{gd}	—	—	92	nC	$V_{GS} = 10V$, See Fig. 6 and 13 ③
$t_{d(on)}$	—	12	—	ns	$V_{DD} = 125V$
t_r	—	14	—	ns	$I_D = 12A$
$t_{d(off)}$	—	67	—	ns	$R_G = 2.5\Omega$
t_f	—	20	—	ns	$R_D = 10\Omega$, See Fig. 10 ④
L_D	—	4.5	—	nH	Between lead, 6mm (0.25in.) from package and center of die contact
L_S	—	7.5	—	nH	
C_{iss}	—	2400	—	pF	$V_{GS} = 0V$
C_{oss}	—	360	—	pF	$V_{DS} = 25V$
C_{rss}	—	170	—	pF	$f = 1.0MHz$, See Fig. 5

Source-Drain Ratings and Characteristics

Parameter	Min.	Typ.	Max.	Units	Conditions
I_S	—	—	20	A	MOSFET symbol showing the integral reverse p-n junction diode.
I_{SM}	—	—	80	A	
V_{SD}	—	—	1.5	V	$T_J = 25^\circ\text{C}, I_S = 12A, V_{GS} = 0V$ ③
t_{rr}	—	340	500	ns	$T_J = 25^\circ\text{C}, I_F = 12A$
Q_{rr}	—	3.5	5.3	μC	$di/dt = 100A/\mu s$ ④
t_{on}	Intrinsic turn-on time is negligible (turn-on is dominated by $L_S + L_D$)				

Notes:

① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)

③ $I_{SD} \leq 12A, di/dt \leq 260A/\mu s, V_{DD} \leq V_{(BR)DSS}, T_J \leq 150^\circ\text{C}$

② Starting $T_J = 25^\circ\text{C}, L = 5.8mH$
 $R_G = 25\Omega, I_{AS} = 12A$. (See Figure 12)

④ Pulse width $\leq 300\mu s$; duty cycle $\leq 2\%$.

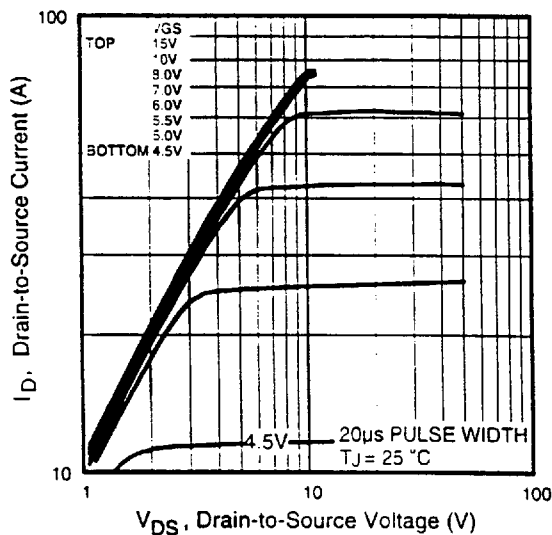


Fig 1. Typical Output Characteristics

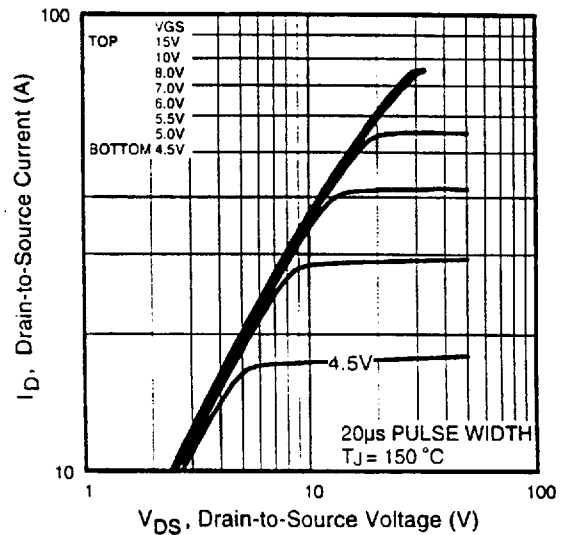


Fig 2. Typical Output Characteristics

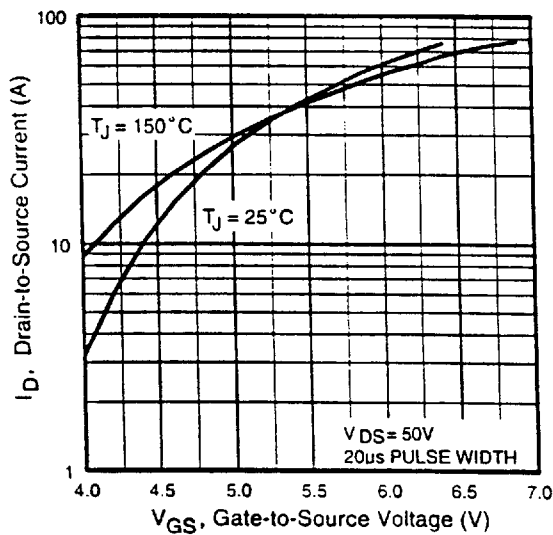


Fig 3. Typical Transfer Characteristics

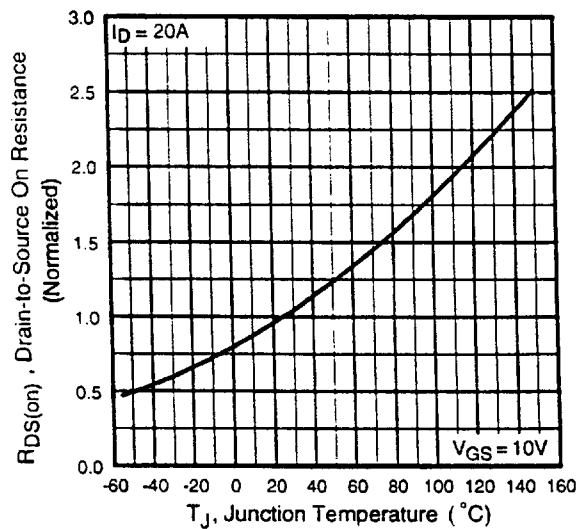


Fig 4. Normalized On-Resistance
Vs. Temperature

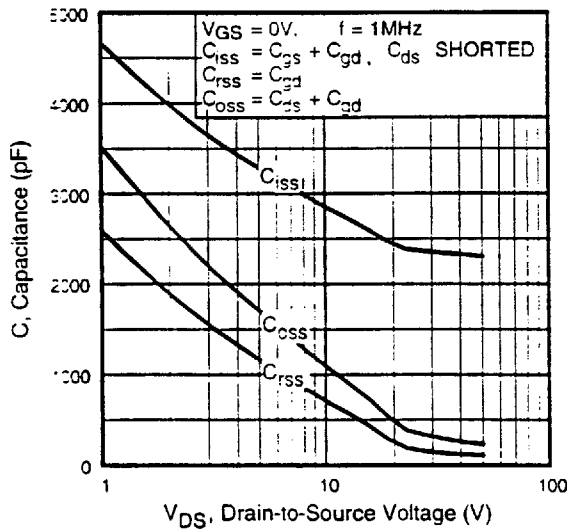


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

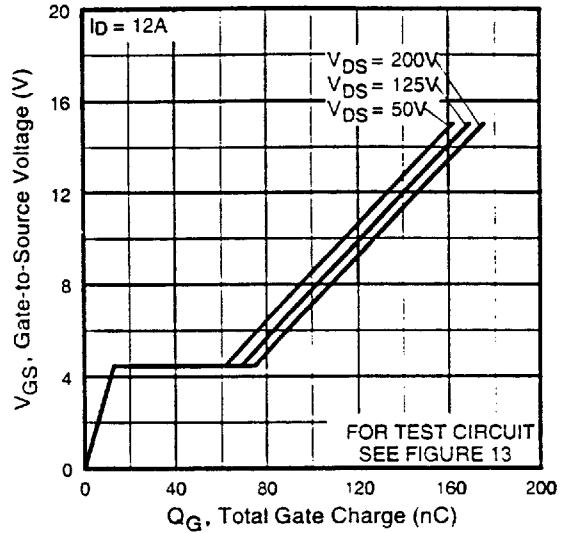


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

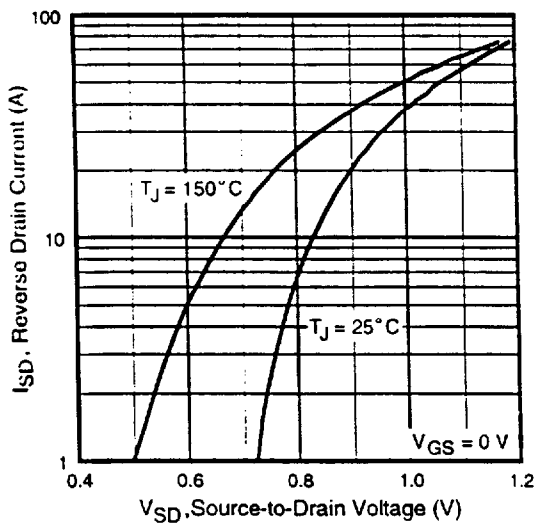


Fig 7. Typical Source-Drain Diode Forward Voltage

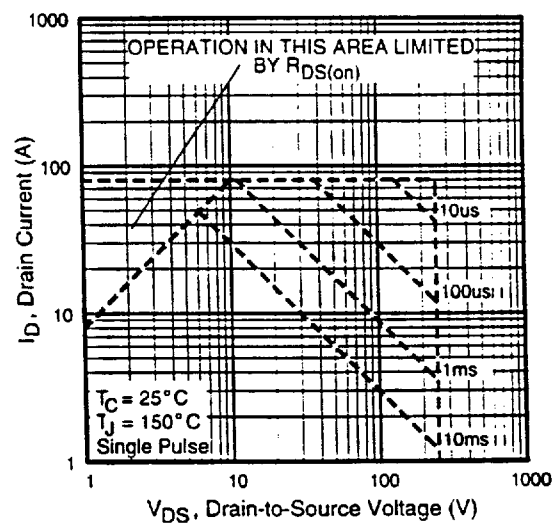


Fig 8. Maximum Safe Operating Area

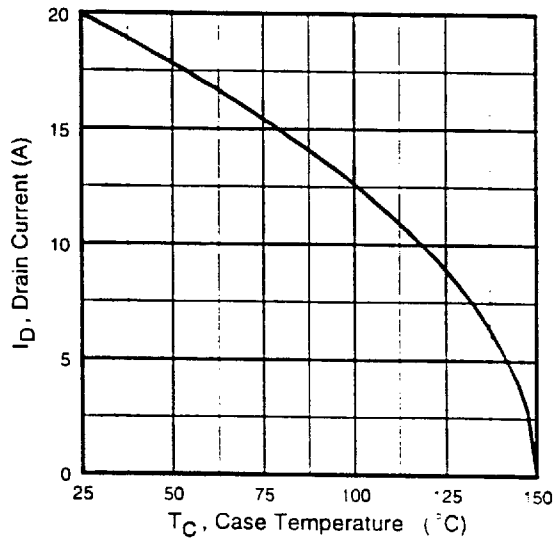


Fig 9. Maximum Drain Current Vs. Case Temperature

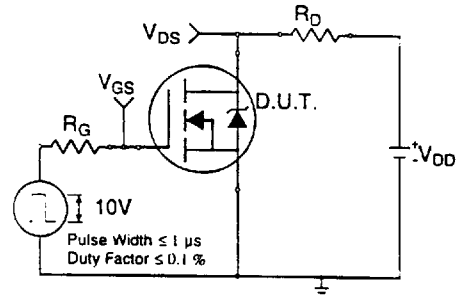


Fig 10a. Switching Time Test Circuit

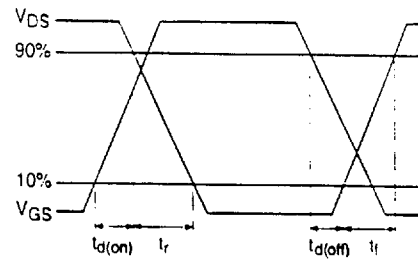


Fig 10b. Switching Time Waveforms

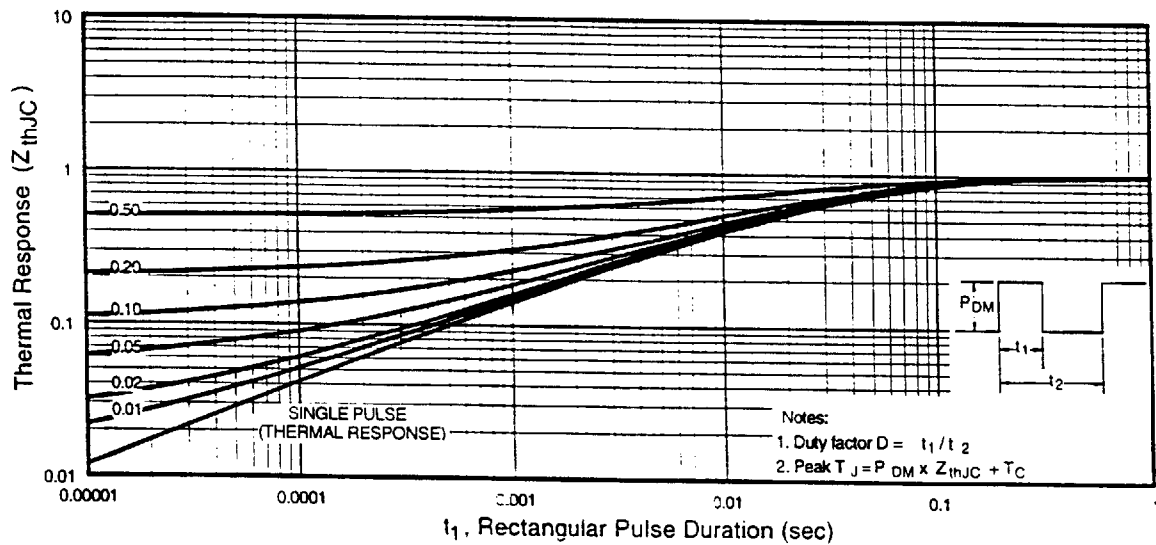


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

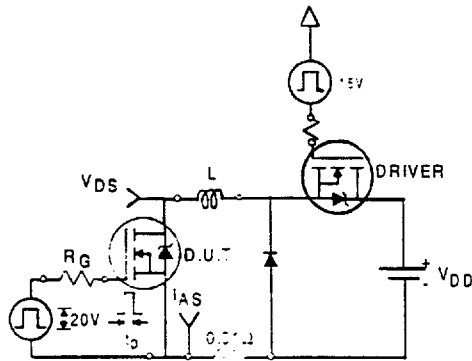


Fig 12a. Unclamped Inductive Test Circuit

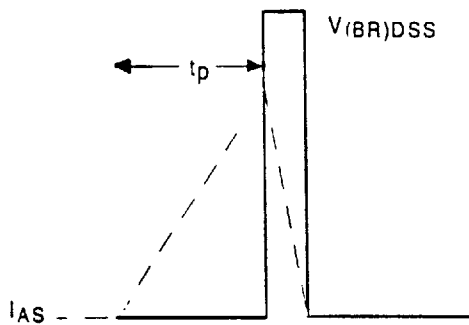


Fig 12b. Unclamped Inductive Waveforms

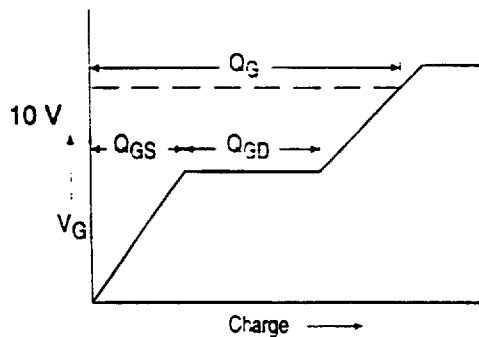


Fig 13a. Basic Gate Charge Waveform

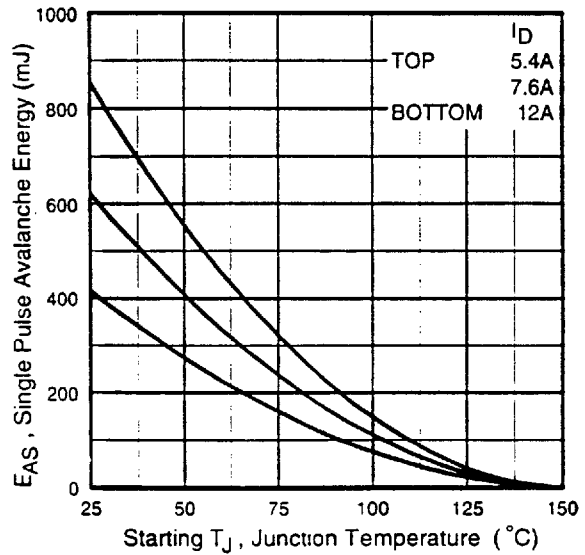


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

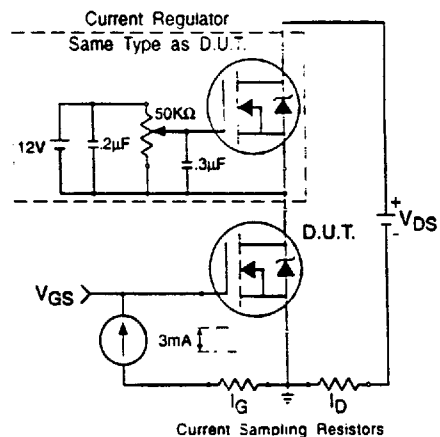
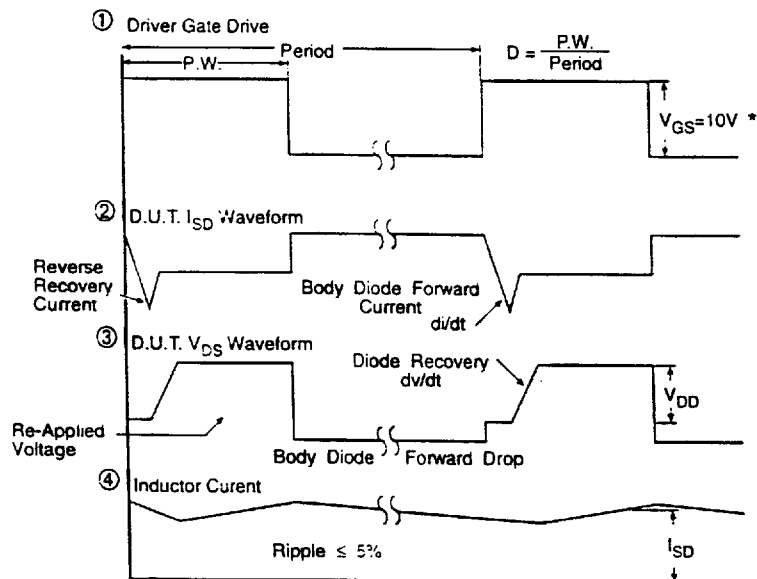
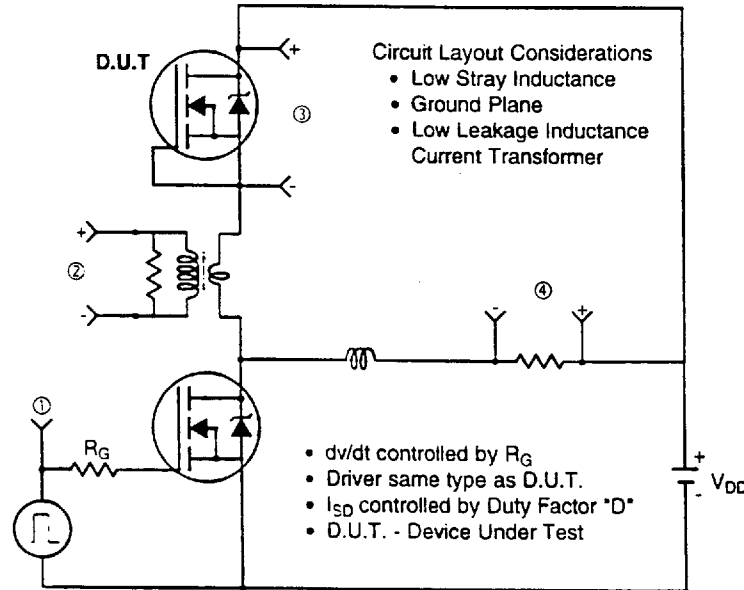


Fig 13b. Gate Charge Test Circuit

Peak Diode Recovery dv/dt Test Circuit



* $V_{GS} = 5V$ for Logic Level Devices

Fig 14. For N-Channel HEXFETS

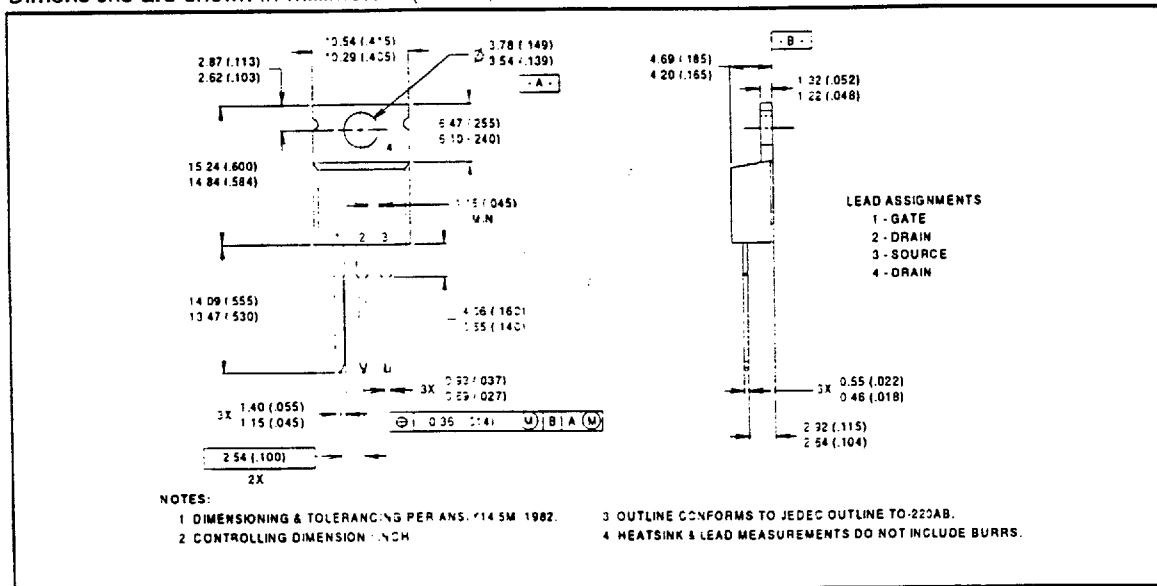
IRF2525

International
IR Rectifier

Package Outline

TO-220AB Outline

Dimensions are shown in millimeters (inches)



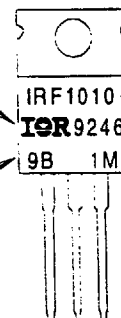
Part Marking Information

TO-220AB

EXAMPLE: THIS IS AN IRF1010
WITH ASSEMBLY
LOT CODE 9B1M

INTERNATIONAL
RECTIFIER
LOGO

ASSEMBLY
LOT CODE



PART NUMBER

DATE CODE
(YYWW)
YY = YEAR
WW = WEEK

International
IR Rectifier

WORLD HEADQUARTERS: 233 Kansas St., El Segundo, California 90245, Tel: (310) 322 3331
EUROPEAN HEADQUARTERS: Hurst Green, Oxted, Surrey RH8 9BB, UK Tel: ++ 44 1883 732020

IR CANADA: 7321 Victoria Park Ave., Suite 201, Markham, Ontario L3R 2Z8, Tel: (905) 475 1897

IR GERMANY: Saalburgstrasse 157, 61350 Bad Homburg Tel: ++ 49 6172 96590

IR ITALY: Via Liguria 49, 10071 Borgaro, Torino Tel: ++ 39 11 451 0111

IR FAR EAST: K&H Bldg., 2F, 30-4 Nishi-Ikebukuro 3-Chome, Toshima-Ku, Tokyo Japan 171 Tel: 81 3 3983 0086

IR SOUTHEAST ASIA: 315 Outram Road, #10-02 Tan Boon Liat Building, Singapore 0316 Tel: 65 221 8371

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Data and specifications subject to change without notice.

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